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(Article begins on next page)

# Simulation software for transition-edge sensor performance prediction

H. Garrone, C. Pepe, A. Reineri, E. Monticone, R. Filippo, and M. Rajteri

**Abstract**—Transition-edge sensors (TES) are outstanding calorimeters based on the steep superconductive transition of a metallic film. Among other photon detectors, they are renowned for the fine energy resolution, the photon-number resolving (PNR) capability and an extremely low dark count rate. Due to the broad detection spectrum, from gamma-ray to visible and submillimetre wavelengths, TESs are highly sought-after in a great variety of fields, such as X-ray detection and quantum technologies. Each of these fields demands a step forward in TESs performance with regards to the recovery time and energy resolution. Here we present a program, primarily capable of predicting the performance of TESs. Using established theoretical and empirical methods we developed a software that allows the users to choose active area, thickness, and material composition of a TES and to calculate its performance. Furthermore, the software can simulate TES properties at different working points. The aim of the software is to minimize the production cost and speed up the overall process for the creation of new devices with improved performance.

**Index Terms**—Transition-edge sensors, low temperature detector, simulation software.

## I. INTRODUCTION

THE SIMULATION of sensors performance is a key aspect for the design of any photon and particle detection experiment. Transition-edge sensors (TESs) are microcalorimeters among the best candidates able to achieve excellent energy resolution together with photon number resolving capability [1],[2],[3]. An energy resolution of 0.11 eV was already reached for infrared photons [4], however, some applications require this outcome to be further improved, for instance the PTOLEMY project requires a particle detector with energy resolution better than 0.05 eV [5]. TESs exploit the steep resistance transition of a metallic film from superconductive to normal state; when a photon is absorbed, it releases its energy causing a temperature rise corresponding to a high resistance increment. The energy resolution is directly dependent on the critical temperature ( $T_C$ ) of the film and the volume of the device. Furthermore, it improves by increasing the steepness of the transition. The  $T_C$  of a TES depends on

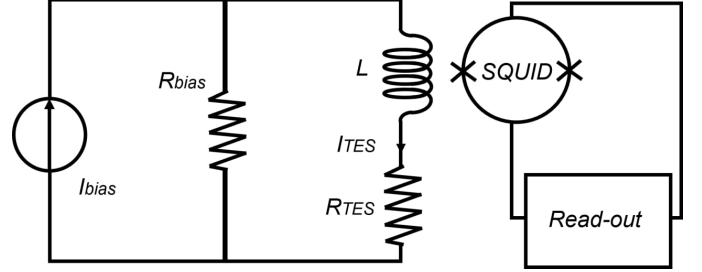


Fig. 1. Schematic of the device bias circuit. The TES is operated in voltage bias mode, a dc-SQUID is used as transimpedance amplifier.

the  $T_C$  of the chosen superconductor and possibly on the proximity effect due to the presence of an additional normal layer [6],[7].

The prediction of TESs performance relies on well known theoretical and empirical models summarised by Irwin and Hilton in [8] as a development from a more general theory for bolometers noise presented in [9]. In section II, the Irwin-Hilton model, the proximity effect [10], the two-fluid and weak-link models [11–14] are summarised. Section III describes how these models are combined into a program that allows the users to simulate and predict TESs performance. In section IV simulated results are compared to literature results and a case study applied to the PTOLEMY project requirement is presented.

## II. PHYSICAL MODEL

### A. Irwin-Hilton configuration

Let a TES be part of an electro-thermal circuit (Fig. 1) and be operated in voltage bias mode; the physics of the system is summarised by the following equation taken from [8]. The current circulating in the TES is:

$$I_{\text{TES}} = \frac{R_{\text{shunt}}}{R_{\text{shunt}} + R_{\text{par}} + R_{\text{TES}}} I_{\text{bias}} \quad (1)$$

where  $R_{\text{TES}}$  is the resistance of the TES,  $R_{\text{par}}$  is the parasitic resistance of the circuit in the TES branch and  $R_{\text{shunt}}$  is a shunt resistance in parallel to the TES.  $I_{\text{bias}}$  is the bias current of the overall circuit.

In stationary thermal conditions the rate of heat flow from the TES to the thermal bath is equal to the power due to the Joule effect, hence  $I_{\text{TES}}$  is equal to:

$$I_{\text{TES}} = \sqrt{\frac{k(T_0^n - T_{\text{bath}}^n)}{R_{\text{TES}}}} \quad (2)$$

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with  $T_0$  the TES temperature in the stationary working condition,  $T_{\text{bath}}$  the temperature of the thermal bath,  $n$  the thermal conductance exponent and  $k = \sum_{i=0}^N A_i \cdot V_i$ . Where  $V_i$  volume and  $A_i$  is the electron phonon coupling constant of the  $i$ th layer of  $N$  layers [15]. The low frequency loop gain of the circuit in stationary state  $\mathcal{L}$  and the characteristic time  $\tau$  of the circuit are defined as:

$$\begin{cases} \mathcal{L} \equiv \frac{I_{\text{TES}}^2 R_{\text{TES}} \cdot \alpha_1}{G T_0} \\ \tau \equiv \frac{C}{G} \end{cases} \quad (3)$$

where  $C$  and  $G$  are the TES thermal capacitance and conductance, respectively, and  $\alpha_1 = \left. \frac{\partial \ln(R)}{\partial \ln(T)} \right|_{T_{\text{TES}}}$  is the logarithmic temperature sensitivity. The photons absorbed by the TES generate electrical signals that are readout through an inductance  $L$  coupled to a dc-SQUID used as transimpedance amplifier. For small values of  $L$  (see [8]), the electrical time constant  $\tau_{\text{el}}$  and the effective thermal time constant  $\tau_{\text{eff}}$  are:

$$\begin{cases} \tau_{\text{el}} = \frac{L}{R_L + R_{\text{TES}}(1 + \beta_1)} \\ \tau_{\text{eff}} = \tau \frac{1 + \beta_1 + \frac{R_L}{R_{\text{TES}}}}{1 + \beta_1 + \frac{R_L}{R_{\text{TES}}} + \left(1 - \frac{R_L}{R_{\text{TES}}}\right) \mathcal{L}} \end{cases} \quad (4)$$

where  $\beta_1 = \left. \frac{\partial \ln(R)}{\partial \ln(T)} \right|_{T_0}$  and  $R_L = R_{\text{shunt}} + R_{\text{par}}$ .

A TES operating in stable conditions can have an overdamped or underdamped response. The stability constraint in the first case is:

$$R_{\text{TES}} > \frac{\mathcal{L} - 1}{\mathcal{L} + 1 + \beta_1} R_L \quad (5)$$

whereas in the underdamped response the constraints are:

$$\mathcal{L} \leq 1 \quad \text{or} \quad \begin{cases} \mathcal{L} > 1 \\ L < \frac{\tau}{\mathcal{L} - 1} [R_L + R_{\text{TES}}(1 + \beta_1)] \end{cases} \quad (6)$$

The energy resolution ( $\Delta E_{\text{FWHM}}$ ) of the TES is influenced by the Johnson noise voltage of the TES ( $S_{V_{\text{TES}}}$ ) and of the load resistor ( $S_{V_{\text{th}}}$ ), the thermal fluctuation noise ( $S_{P_{\text{TFN}}}$ ) and SQUID amplifier noise ( $S_{\text{SQUID}}$ ).  $\Delta E_{\text{FWHM}}$  is calculated as:

$$\begin{aligned} \Delta E_{\text{FWHM}} &= 2\sqrt{2\ln 2} \times \\ &\times \left\{ \frac{\tau I_0^2}{\mathcal{L}^2} \left[ \left( \frac{\mathcal{L}^2}{I_0^2} S_{P_{\text{TFN}}} + S_{V_{\text{TES}}} + (\mathcal{L} - 1)^2 S_{V_{\text{th}}} \right) \times \right. \right. \\ &\times (S_{V_{\text{TES}}} + S_{V_{\text{th}}}) + \\ &\left. \left. + (\mathcal{L}(R_{\text{TES}} - R_L) S_{\text{SQUID}})^2 \right]^{\frac{1}{2}} \right\}^{\frac{1}{2}}. \end{aligned} \quad (7)$$

with  $S_{V_{\text{th}}} = 4k_B T_0 R_L$ ,  $S_{V_{\text{TES}}} = 4k_B T_0 R_{\text{TES}} \chi(I)$  and  $S_{P_{\text{TFN}}} = 4k_B T_0^2 G \cdot F(T_0, T_{\text{bath}})$ . The term  $\chi(I)$  is introduced to take into account the resistor non-linear current dependency

and  $F(T_0, T_{\text{bath}})$  is the correction due to non-linear dependency of  $G$  from temperatures, (more details in [16]). A simplified version of this formula is:

$$\Delta E = 2\sqrt{2\ln 2} \sqrt{4k_B T_0^2 \frac{C}{\alpha_1} \sqrt{\frac{n}{2}}} \quad (8)$$

To be thorough, we report the formulas that were used to compute the thermal capacitance, the thermal conductance and the TES saturation energy.

Thermal capacitance [17]:

$$C = (2.43 \cdot \gamma T_0 + \zeta T_0^3) V \quad (9)$$

where  $V$  is the volume,  $\gamma$  is the Sommerfeld constant and  $\zeta = \frac{12.3 \cdot \pi^4 R}{5 \cdot T_D^3} \frac{D}{W}$ .  $W$  is the atomic weight,  $D$  is the volumic density,  $T_D$  is the Debye temperature, and  $R$  the gas constant.

Thermal conductance [17]:

$$G = nk T_0^{n-1}. \quad (10)$$

Saturation energy  $E_{\text{sat}}$  is [18]:

$$E_{\text{sat}} = C \Delta T \approx \frac{C T_0}{\alpha_1}. \quad (11)$$

### B. Proximity effect

A bilayer, made up of a superconductor layer and a normal metal layer, has a critical temperature  $T_C$  lower than the intrinsic critical temperature  $T_{C0}$  of the superconductor due to the proximity effect. Assuming the layers thicknesses to be comparable with the coherence length of the materials, one can express the overall  $T_C$  of the bilayer as follows [10]:

$$T_C = T_{C0} \left[ \frac{d_s}{d_0} \frac{1}{1.13 \left(1 + \frac{1}{a}\right) t} \right]^a \quad (12)$$

where  $t$  is the transmission coefficient,  $\frac{1}{d_0} = \frac{\pi}{2} k_B T_{C0} n_s \lambda_F^2$ , with  $\lambda_F$  the Fermi wavelength, and the exponent  $a$  equal to:

$$a = \frac{d_n n_n}{d_s n_s}. \quad (13)$$

The terms  $d_n$  and  $d_s$  are the thicknesses and  $n_n$ ,  $n_s$  are the electron state densities of normal and superconductive layers, respectively. For normal layer thickness greater than 50 nm we used the transmission coefficient modified formula [10]:

$$\frac{1}{t} \rightarrow \frac{1}{t} + \frac{1}{3} \frac{d_n}{\sigma_n} \frac{2G_k}{\left(\frac{\lambda_F}{2}\right)^2} \quad (14)$$

where  $G_k = \frac{e^2}{h}$  and  $\sigma_n$  stands for the normal layer conductivity.  $e$  is the electron charge and  $h$  is the Planck constant.

### C. Transition models

The parameters  $\alpha_1$  and  $\beta_1$  can be extrapolated through models that describe the resistance dependency with respect to the current and the temperature. In [11], Ullom *et al.* summarise the two most commonly used models. One is the two-fluid model and the other is the weak-link model. In both these models the resistance is expressed as a function of the TES current  $I_{\text{TES}}$  and of the critical current  $I_C$ .  $I_C$  is a function of the TES temperature  $T_0$  and the critical temperature  $T_C$ .

1) *Two-fluid model*: In the two-fluid model the critical current is:

$$I_C(T_0) = I_{C0} \left(1 - \frac{T_0}{T_C}\right)^{\frac{3}{2}} \quad (15)$$

whereas the resistance expression is:

$$R(I_{\text{TES}}, T_0) = c_R R_N \left(1 - c_1 \frac{I_C(T_0)}{I_{\text{TES}}}\right) \quad (16)$$

where  $I_{C0} = I_C(0)$ ,  $R_N$  is the normal resistance and  $c_R$ ,  $c_1$  are phenomenological parameters describing the normal and superconductive carriers channels. Thus the parameters  $\beta_1$  and  $\alpha_1$  are obtained as follows [19]:

$$\beta_1 = c_R \frac{R_N}{R_{\text{TES}}} - 1 \quad (17)$$

$$\alpha_1 = \frac{3}{2} \left[ \beta_1^{\frac{1}{3}} \left( \frac{(\beta_1 + 1) c_1 I_{C0}}{I_{\text{TES}}} \right)^{\frac{2}{3}} - \beta_1 \right]. \quad (18)$$

2) *Weak-link model*: With the assumption that the distance between the leads is comparable to the effective coherent length of the superconductor, the resistance is given by [11]:

$$R(I_{\text{TES}}, T_0) = R_N \left[ 1 - \left( \frac{I_C(T_0)}{I_{\text{TES}}} \right)^2 \right]^{\frac{1}{2}}. \quad (19)$$

On the other hand,  $I_C$  shows an exponential decrease with respect to the length. A compact form of the formula is [11]:

$$I_C(T_0, l) = I_{C0} V^* \frac{l}{\xi^*} \exp\left(-\frac{l}{\xi^*}\right) \quad (20)$$

with  $l$  being the weak-link length.  $\xi^*$  is the effective decay length for arbitrary  $T_{Ci}$  calculated in the framework of the Usadel equations by Kupriyanov *et al.* [20] as:

$$\xi^*(T_0) = \xi_N \sqrt{\frac{T_{CL}}{T_0} \left[ 1 + \frac{\pi^2}{4} \ln^{-1}\left(\frac{T_0}{T_{CL}}\right) \right]} \quad (21)$$

where  $T_{Ci}$  is the intrinsic critical temperature of the weak-link,  $T_{CL}$  is the critical temperature of the leads and  $\xi_N$  is the intrinsic coherent length of the material at  $T > T_{Ci}$ .

Whereas  $V^*$  has the analytic expression:

$$V^*(T_0) = \frac{32 \cdot T_0 \cdot \Delta^2}{T_{CL} [\mathcal{E} + \Delta^* + \sqrt{2\Delta^*(\mathcal{E} + \Delta^*)}]^2} \quad (22)$$

with  $\mathcal{E} = \pi k_B T_0$ ,  $\Delta^*(T_0) = \sqrt{(\pi k_B T_0)^2 + \Delta^2}$  and the gap in the isotropic superconductive electrodes  $\Delta$  is well approximated as:

$$\Delta = 1.76 \cdot k_B T_0 \tanh \left[ \frac{\pi}{1.76} \sqrt{\left( \frac{T_{CL}}{T_0} - 1 \right)} \right] \quad (23)$$

Then the parameter  $\alpha_1$  is finally obtained deriving the critical current with respect to the temperature, whereas  $\beta_1$  has an expression similar to the one derived in the two-fluid model:

$$\alpha_1 = - \left( \frac{R_N}{R_{\text{TES}}} \frac{I_C(T_0)}{I_{\text{TES}}} \right)^2 \frac{\partial \ln(I_C)}{\partial \ln(T)} \Big|_{T_0} \quad (24)$$

$$\beta_1 = \left( \frac{R_N}{R_{\text{TES}}} \right)^2 - 1 \quad (25)$$

In both these models, an approximation of  $I_{C0}$  is given by [21]:

$$I_{C0} = 3.52 \sqrt{\frac{k_B C}{\hbar R_N}} T_C \quad (26)$$

3) *Critical exponent model*: Besides the previous two models, the resistance can be expressed in the form of critical exponent formulation as:

$$R = \frac{R_N}{1 + e^{4.4 \cdot \frac{(T_C - T)}{\Delta T}}} \quad (27)$$

where  $\Delta T = T(R_{\text{TES}} = 90 \% \cdot R_N) - T(R_{\text{TES}} = 10 \% \cdot R_N)$ . The value of  $\alpha_1$  is obtained through its definition with this expression of the resistance.

### III. SOFTWARE

Here we present a program which exploits the models discussed in the previous section. The program is based on *G Web Development Software*, a programming environment developed by *National Instrument*. The ansatzes for this program are: rectangular TESs and  $T_0 = T_C$ . The flowchart diagram of the program is shown in Fig. 2.

Firstly the user chooses the materials, enters the active area parameters and the thickness of each of the selected layers. The program has a precompiled list of common used materials in literature, with their related parameters, however the user is allowed to modify them.

The second step is to manually enter the value of  $T_C$ , or allow the program to automatically calculate it, using the proximity effect model. In the latter scenario the user must choose two layers only, and enter the value of  $t$ .

The third step is the choice of the model. The first option is the manual mode, the program requires to enter the values of  $\alpha_1$  and  $\beta_1$ , or enable the critical exponent calculation and enter the value of  $\beta_1$  and  $\Delta T$ . Instead, if the weak-link model option is selected, the user must enter the values of the following parameters:  $I_{C0}$ ,  $\xi_N$ ,  $T_{Ci}$  and  $T_{CL}$ . In the third option,  $I_{C0}$ ,  $c_R$  and  $c_1$  are required as inputs to exploit the two-fluid model. The parameter  $I_{C0}$  could be entered by the user or automatically computed by (26). After the determination of  $\alpha_1$  and  $\beta_1$ , the fourth step consists in the choice between calculating  $\Delta E$  with the complete formula

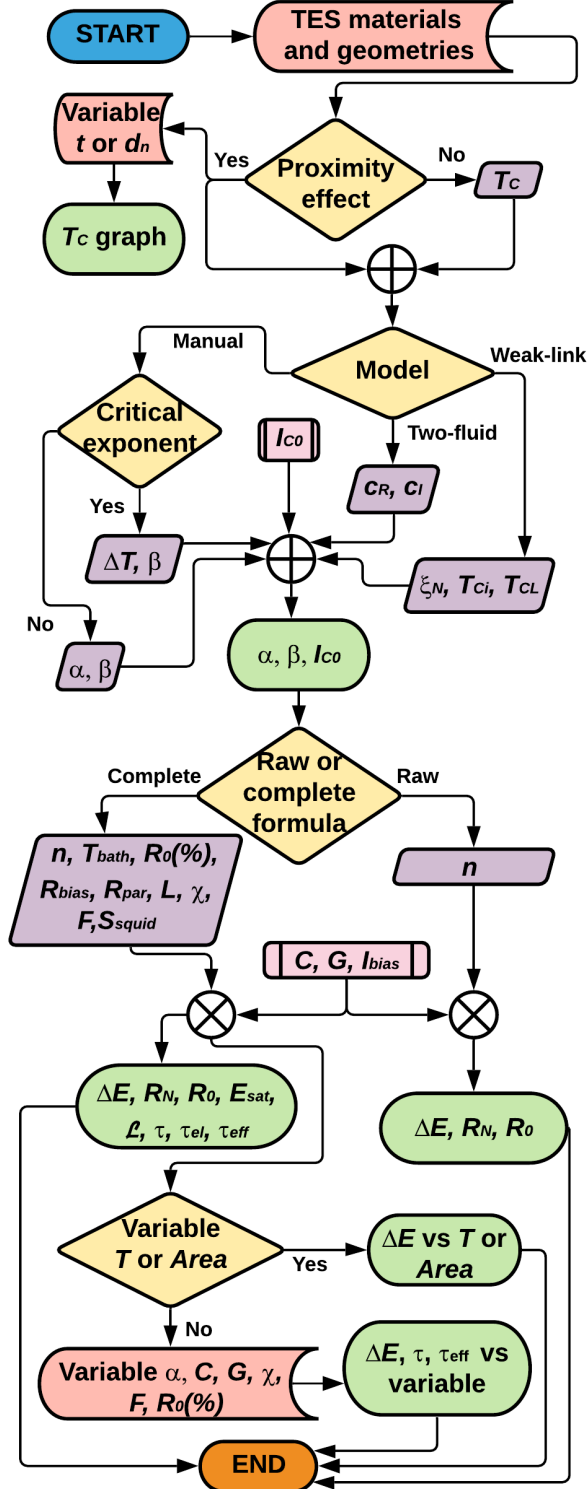


Fig. 2. Flowchart of the program. Oval is used as *terminal*, diamond as *decision*, half-cylinder as *stored data*, parallelogram as *input*, rectangular as *sub-routine*, vertical cross as *or* and diagonal cross as *and*.

(7) and a simplified one (8). If the complete formula is selected, the following inputs are required:  $n$ ,  $L$ ,  $T_{\text{bath}}$ ,  $R_{\text{shunt}}$ ,  $R_{\text{par}}$ ,  $R_{\text{TES}}(\%)$  ( $R_{\text{TES}}$  as a percentage of  $R_N$ ) to characterize

the electro-thermal circuit and  $F(T_0, T_{\text{bath}})$ ,  $\chi(I)$ ,  $S_{\text{SQUID}}$ . It is possible to enable the manual insertion of the values of  $C$  and  $G$  and optionally insert a value for  $I_{\text{BIAS}}$ , which leads to the computation of  $I_{\text{TES}}$  through (1) instead of (2). In addition to  $\Delta E$ , the standard outputs of the simulation are:  $R_N$ ,  $R_{\text{TES}}$ ,  $I_{\text{TES}}$ ,  $C$ ,  $G$ ,  $E_{\text{sat}}$ ,  $\mathcal{L}$ ,  $\tau$ ,  $\tau_{\text{el}}$ ,  $\tau_{\text{eff}}$  and two boolean indicators for the stability conditions. Moreover, the tool allows to simulate many curves inserting, as inputs, a start value, an end value and a step value.

As an example, if the proximity effect is enabled, the graphs of  $T_C$  vs.  $t$ ,  $d_n$  or  $d_s$  can be generated. It is also possible to select, as independent variable in the graph, one from  $S_{\text{Area}}$ ,  $T_C$ ,  $R_{\text{TES}}(\%)$ ,  $R_{\text{shunt}}$ ,  $R_{\text{par}}$ ,  $n$ ,  $L$ ,  $I_{\text{BIAS}}$ ,  $C$ ,  $G$ ,  $\alpha_1$ ,  $F(T_0, T_{\text{bath}})$ ,  $\chi$ ,  $d_s$ ,  $d_n$ ,  $t$ , the TES length or the TES width, while, the dependent variable could be one from:  $\Delta E_{\text{FWHM}}$ ,  $E_{\text{sat}}$ ,  $\mathcal{L}$ ,  $\tau_{\text{el}}$ ,  $\tau_{\text{eff}}$ ,  $C$ ,  $G$ ,  $T_C$ ,  $\alpha_1$  and  $\beta_1$ .

Therefore, this program not only computes the energy resolution or the other important TESs features, but it also simulates their trends taking into account every dependency. For example, let's consider that  $T_C$ ,  $\alpha_1$  and  $\beta_1$  are calculated from one of the described model and that the user wants to study the trend of  $\Delta E_{\text{FWHM}}$  versus  $d_s$ . Therefore, this program computes, for all the values of the thickness, the correspondent values of  $T_C$ ,  $C$  and  $G$ . Also  $R_N$  is evaluated for each thickness and consequently  $R_{\text{TES}}$  and  $I_{\text{TES}}$ . Then  $I_{C0}$  and hence  $\alpha_1$  are computed considering the variation of  $d_s$ . Finally, the trend of  $\Delta E_{\text{FWHM}}$  versus thickness is obtained considering all the dependencies.

#### IV. COMPARISON AND RESULTS

##### A. Comparison between simulated and measured results

In Table I, the measured values of  $C$ ,  $G$ ,  $\tau_{\text{eff}}$  and  $\Delta E_{\text{FWHM}}$  are compared to the ones computed by our software for three TESs. The aim of this comparison is to verify the trustworthiness of the software. The comparison is performed for the TESs described in [4], [21–24] from which a rich set of parameters and results is available. TES1, TES2, TES4 and TES5 are TESs characterized for application in the optical range (eV), whereas TES3 was used in the detection of x-rays (keV). The relative deviation between simulated and measured results of  $\tau_{\text{eff}}$  is less than 16 % for the five cases. While energy resolutions can be computed exactly for TES1, TES2, TES4 and TES5 assuming  $\chi(I)$  in a range from 1 to 15. In case of TES3 the thermal capacitance was used as input in order to take into account also for the presence of the absorber. For TES3, the excess noise is evaluated as  $\chi(I) = (1 + 2\beta_1)(1 + M^2) = 66$ , considering  $M^2 \sim 10$  at  $R_{\text{TES}} = 30\%$  and  $\beta_1 = 2.5$  as reported in [23]. With this value our software compute  $\Delta E_{\text{FWHM}} = 2.3$  eV, that corresponds to a relative deviation of 8 %.

##### B. Simulation for PTOLEMY project

To achieve the target of 0.05 eV energy resolution required in the PTOLEMY project we are developing thin

TABLE I  
COMPARISON TABLE

	TES1		TES2		TES3		TES4		TES5		
Inputs											
Reference	[4]		[22]		[23]		[21]		[24]		
Model in the simulation	manual		two-fluids		manual		two-fluids		two-fluids		
Materials	Ti/Au		Ti/Au		Ti/Au		Ti		Ti/Au		
$S_{\text{Area}}$ ( $\mu\text{m}^2$ )	100	-	100	-	4200	-	400	-	64	-	
$T_{\text{C}}$ (mK)	106	-	301.5	-	89.5	-	470	-	279.8	-	
Outputs											
$C$ ( $\frac{\text{fJ}}{\text{K}}$ )	0.35	0.36	n.p.	1.25	900	-	4.7	4.3	n.p.	0.3	
$G$ ( $\frac{\text{pW}}{\text{K}}$ )	44	44	n.p.	1589	117	117.8	110	-	n.p.	246.6	
$\tau_{\text{eff}}$ ( $\mu\text{s}$ )	3.8	4.1	0.186	0.187	260	260.4	2.8	2.4	0.155	0.150	
$\Delta E$ (eV)	0.11	0.11	0.26	0.26	2.5	2.3	0.52	0.52	0.21	0.21	

This table compare the results of the simulations with the data taken from literature for five TESs. The acronyms "n.p." stands for "not present" meaning that data are not reported in the paper and the symbol "-" means that the literature value was used as input in the simulation.

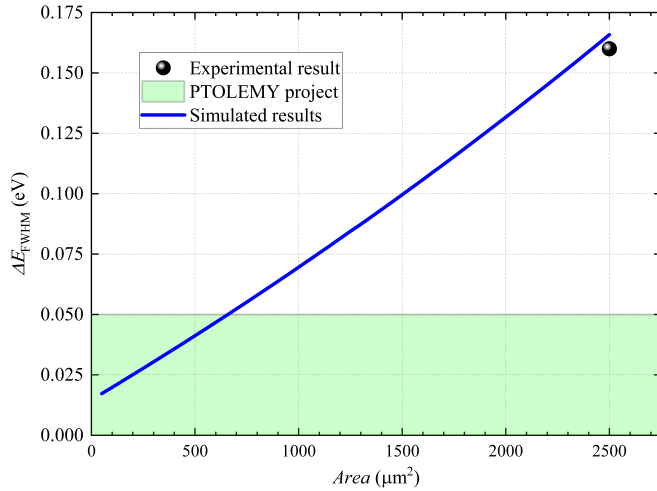


Fig. 3. The graph shows  $\Delta E_{\text{FWHM}}$  measured for a  $2500 \mu\text{m}^2$  Ti/Au TES and expected  $\Delta E_{\text{FWHM}}$  simulated with the software, in both cases  $T_C = 52$  mK. Energy resolution better than 0.05 eV should be achieved for an equivalent TES with an active area below  $650 \mu\text{m}^2$ .

Ti/Au TESs. The volume and the critical temperature are the two properties we are playing with to achieve the project goal, in fact, a small volume and a low  $T_C$  should guarantee an excellent energy resolution. However, we also aim to maximise the active area and optimize the  $T_C$  for the experimental system in which the detector will be used. For a Ti/Au bilayer the minimum Ti layer thickness that we are able to achieve preserving the superconductive properties is 12 nm. The minimum target value of  $T_C$  suitable for our system is between 50-60 mK. Considering these two constraints we studied the trend of  $T_C$  with respect to Au layer thickness with our program. From the simulation we apprehended that the superconductive transition of a Ti/Au bilayer with 12 nm and 30 nm thickness, respectively, is 58 mK. We fabricated and characterized a Ti/Au TES with an active area of

$2500 \mu\text{m}^2$  and the bilayer thicknesses reported above. The critical temperature resulted to be 52 mK, the thermal conductance 50 pW/K and the capacitance 2.5 fJ/K. With a bath temperature of 30 mK and a working point at 12 % of  $R_N$ , we measured an energy resolution of 0.16 eV for photons with 0.8 eV energy. We also measured  $\alpha_I = 20$ ,  $\beta_I = 5$  and  $\tau_{\text{eff}} = 47 \mu\text{s}$ . The complete characterization allowed us to replicate these results in our program and moreover simulate the energy resolution of an equivalent TES for different active areas. The graph in Fig. 3 shows the obtained experimental result and the results from the simulation. The target set by the PTOLEMY project is represented by the green area, according to the simulation, a TES with an area below  $650 \mu\text{m}^2$  should satisfy this requirement.

## V. CONCLUSIONS

We have developed a simulation program that is a useful tool to predict and simulate the behaviour of rectangular TESs. The software has been tested through a comparison between literature and simulated results. We were able to simulate TESs performance in a broad range of applications, from optical to x-ray detection. The comparisons between the effective thermal time constants show an agreement within 16 %. The energy resolution, in case of optical TESs, matched with the experimental data while, for x-rays the agreement is within 8 %. The program is an effective tool that we are applying to the design phase of particle detection experiments. For PTOLEMY project, our simulation program was exploited to design the thicknesses required for the desired  $T_C$  and then to find the maximum area of the TES that could satisfy the project requirement. The program calculates TESs performances, whose agreement with the experimental data improves all the more devices parameters are known.

We provide a free access to the software as web application at url <https://tes.inrim.it/>.

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